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Aehr Test Systems Receives Orders Exceeding \$2.5 Million for Burn-in and Test Products for Automotive Semiconductor Devices

Fremont, CA (February 13, 2018) – Aehr Test Systems (NASDAQ: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, today announced that it has received orders totaling more than \$2.5 million for products and services from a leading multi-national manufacturer of advanced logic integrated circuits (ICs) for automotive applications.

The products in these orders add capabilities required to burn-in and test the latest automotive parts, which implement features such as advanced driver assistance systems (ADAS). Services within the orders reflect the support that Aehr Test offers to its production customers at their sites worldwide, which includes on-site service and applications engineers. Aehr Test service and applications engineers partner with customers to ensure effective production operation and integration with factory data and traceability systems in addition to support for qualification of new devices and the transition from development to production.

Gayn Erickson, President and CEO of Aehr Test Systems, commented, "We are very pleased to receive these additional orders for products and services from this major semiconductor customer. Our test and burn-in systems are a key part of this customer's quality and reliability program for their expanding line of automotive products.

"The rapid growth and increasing demand for reliability in automotive sensor technologies is a key market driver for Aehr Test. These technologies include ADAS capabilities such as collision avoidance systems using laser, LIDAR (Light Detection and Ranging), and RADAR or other sensing technologies. More and more new vehicles now include as standard capabilities collision avoidance systems that detect obstacles and monitor the vehicle's surroundings to notify the driver of dangerous conditions and take evasive action. And it is not just autonomous vehicles that require extremely high reliability of the devices in these systems. More and more vehicles around the world are embedding these systems and sensors into their everyday driving features. We see the rising tide of the increasing number of embedded sensors and electrical and optical systems in vehicles as a key driver of the increasing market need for more and more reliable semiconductors. This, in turn, is increasing the need for 100% production test and burn-in of devices in order to lower the infant mortality rate and ensure that these devices and systems operate over the life of the vehicles.

"The longer life expectancy of both traditional internal combustion engine vehicles and certainly the longer life of hybrid and fully electric vehicles is challenging the suppliers of these systems to ensure a higher level of reliability and longer life than ever expected in vehicles of the past. This will be a key topic of the semiconductor industry's Burn-in and Test Conference to be held in Mesa, Arizona early next month."

Mr. Erickson will be presenting the Keynote address to the attendees of this year's Burn-in and Test Strategies Workshop conference on March 5, 2018. The conference is being held from March 5 – 7, 2018 at the Hilton Conference Center in Mesa, Arizona. More information on this conference can be obtained at <u>www.bitsworkshop.org</u>.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic, optical and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, incremental capacity needs, and new opportunities for Aehr Test products in package, wafer level, and singulated die/module level test. Aehr Test has developed and introduced several innovative products, including the ABTS[™] and FOX-P[™] families of test and burn-in systems and FOX WaferPak Aligner, FOX-XP WaferPak Contactor, FOX DiePak Carrier and FOX DiePak Loader. The ABTS system is used in production and qualification testing of packaged parts for lower power and higher power logic devices as well as all common types of memory devices. The FOX-XP system is a full wafer contact and singulated die/module test and burn-in system used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers, systems-on-achip, and integrated optical devices. The WaferPak contactor contains a unique full wafer probe card capable of testing wafers up to 300mm that enables IC manufacturers to perform test and burn-in of full wafers on Aehr Test FOX systems. The DiePak Carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of both bare die and modules. For more information, please visit Aehr Test System's website at www.aehr.com.

Safe Harbor Statement

This press release contains certain forward-looking statements based on current expectations, forecasts and assumptions that involve risks and uncertainties. These statements are based on information available to Aehr Test as of the date hereof and actual results could differ materially from those stated or implied due to risks and uncertainties. Forward-looking statements include statements regarding Aehr Test's expectations, beliefs, intentions or strategies regarding its products, including statements regarding future market opportunities and conditions, expected product shipment dates and customer orders or commitments. These risks and uncertainties include, without limitation, customer demand and acceptance of Aehr Test's products, the ability of new products to meet customer needs or perform as described, as well as general market conditions and Aehr Test's ability to execute on its business strategy. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission for a more detailed description of the risks facing Aehr Test's business. Aehr Test disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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